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# **X-ray Diffraction Imaging of Nanoscale Materials and Biological Structures**

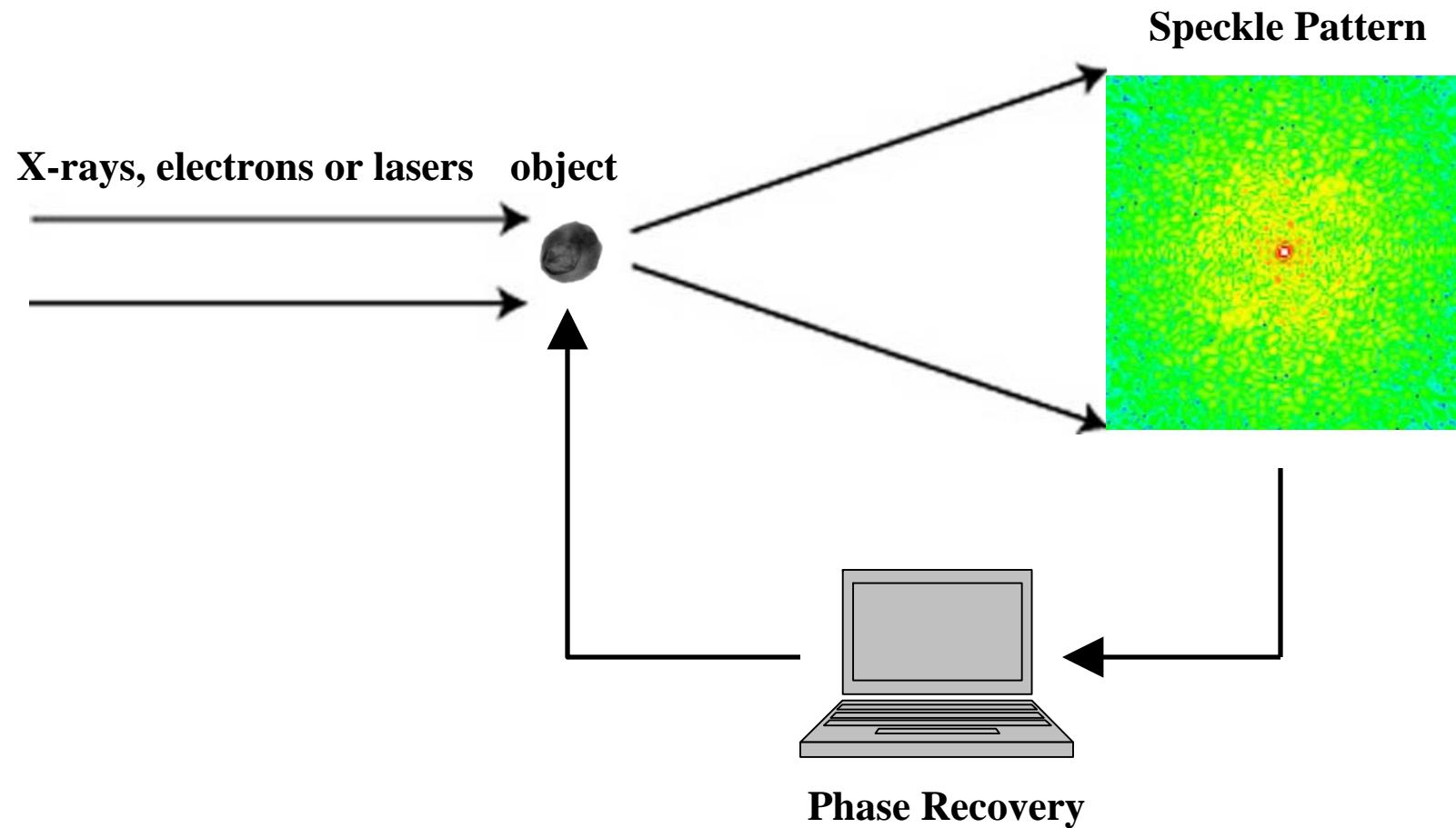
John Miao

*Dept. of Physics & Astronomy and California NanoSystems Institute  
University of California, Los Angeles*

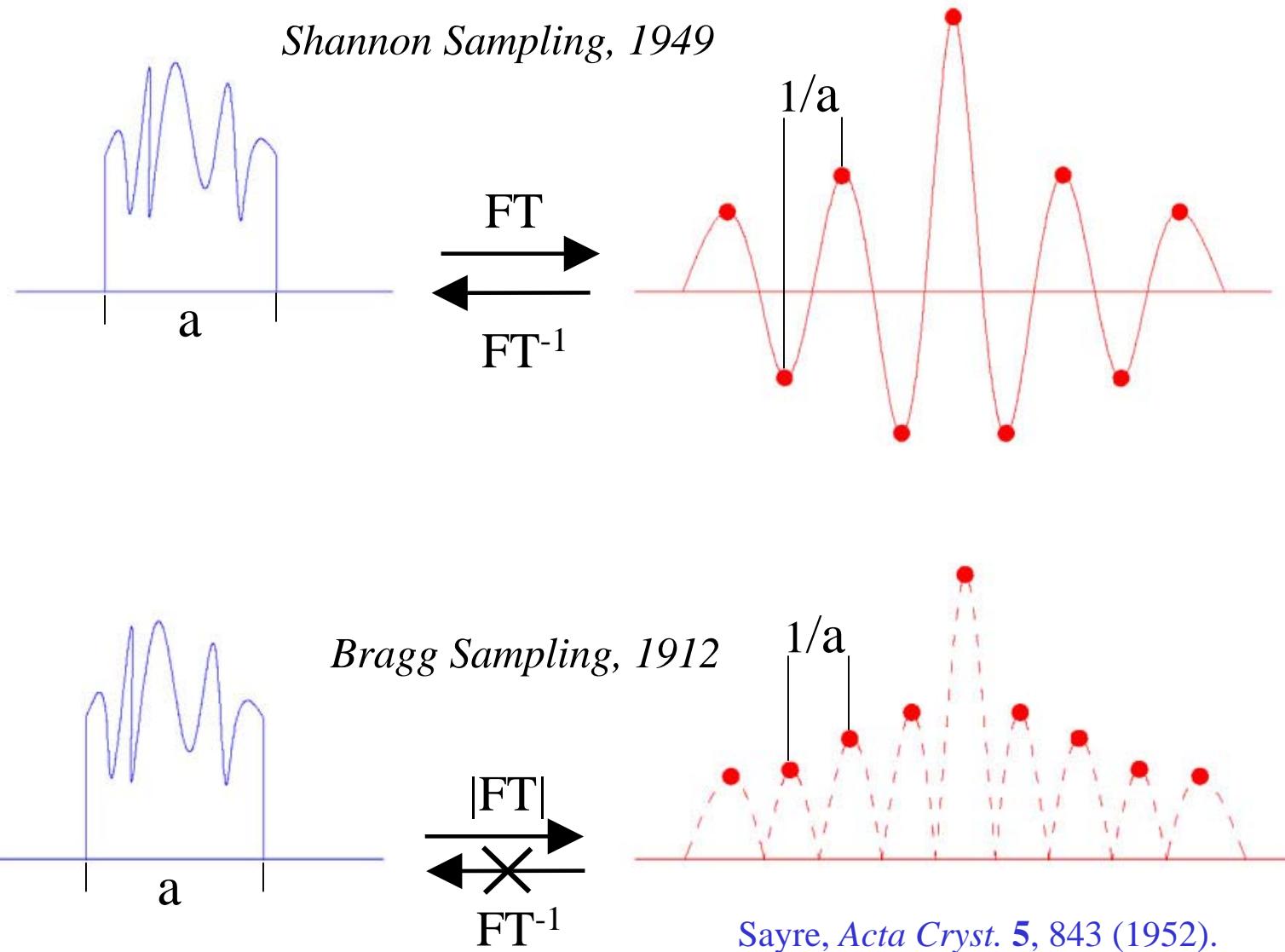
NSLS-II Coherent X-ray Diffraction Workshop, March 14, 2008

## Coherent Diffraction Microscopy (or Lensless Imaging)

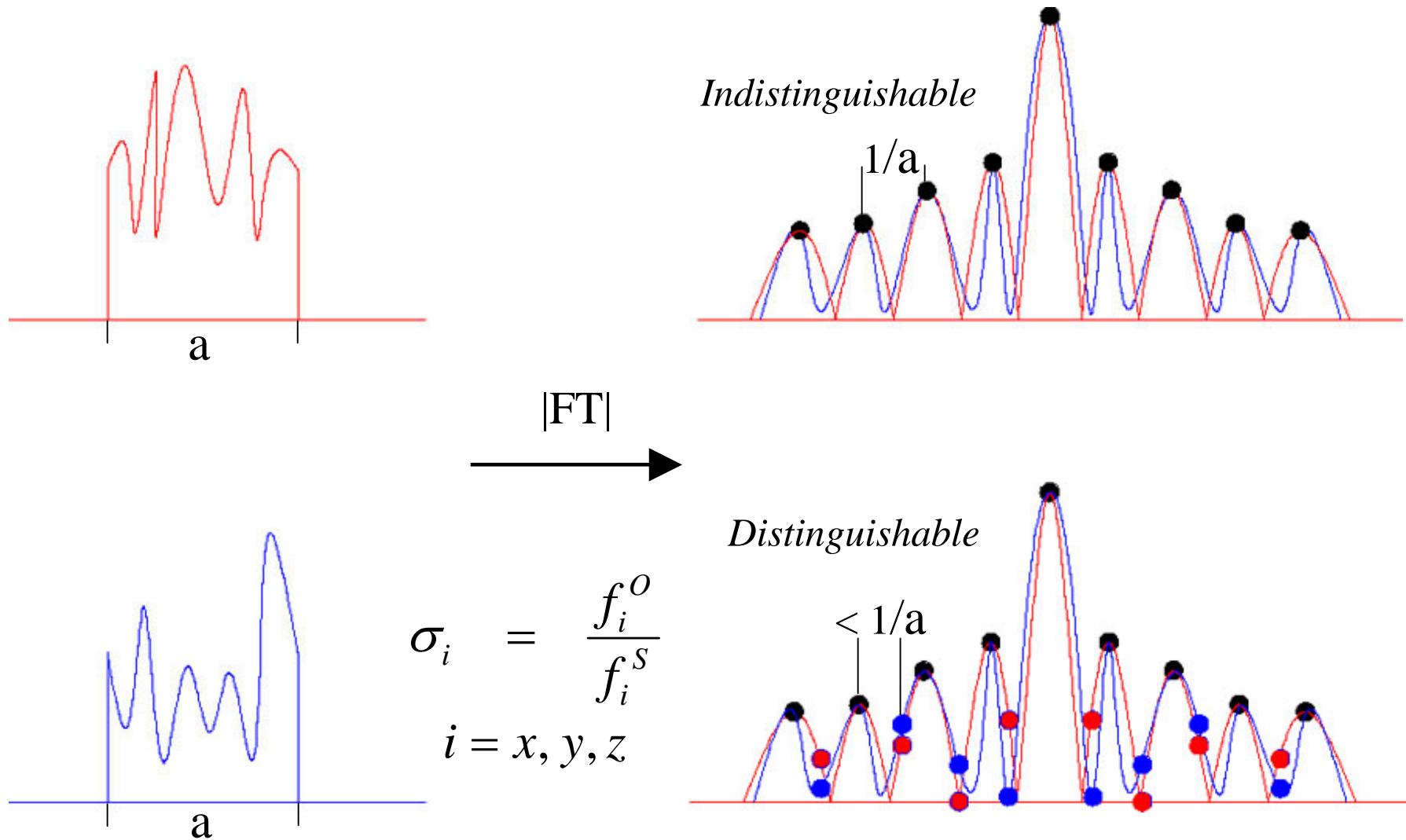
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## Shannon Sampling vs. Bragg Sampling

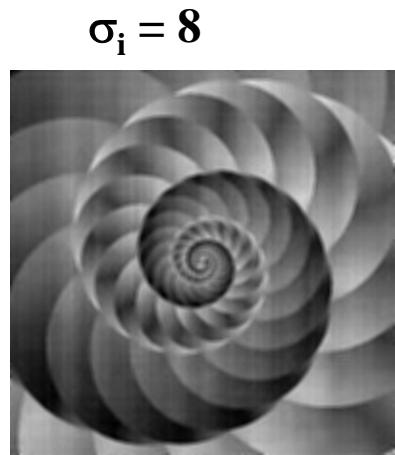
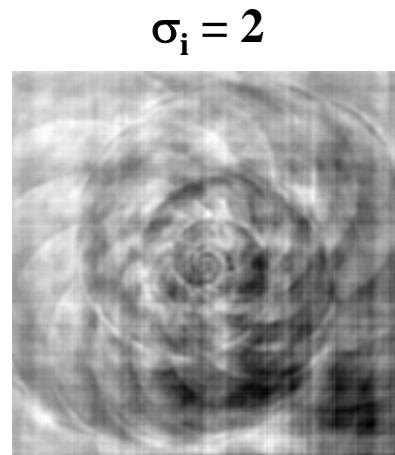


## Oversampling

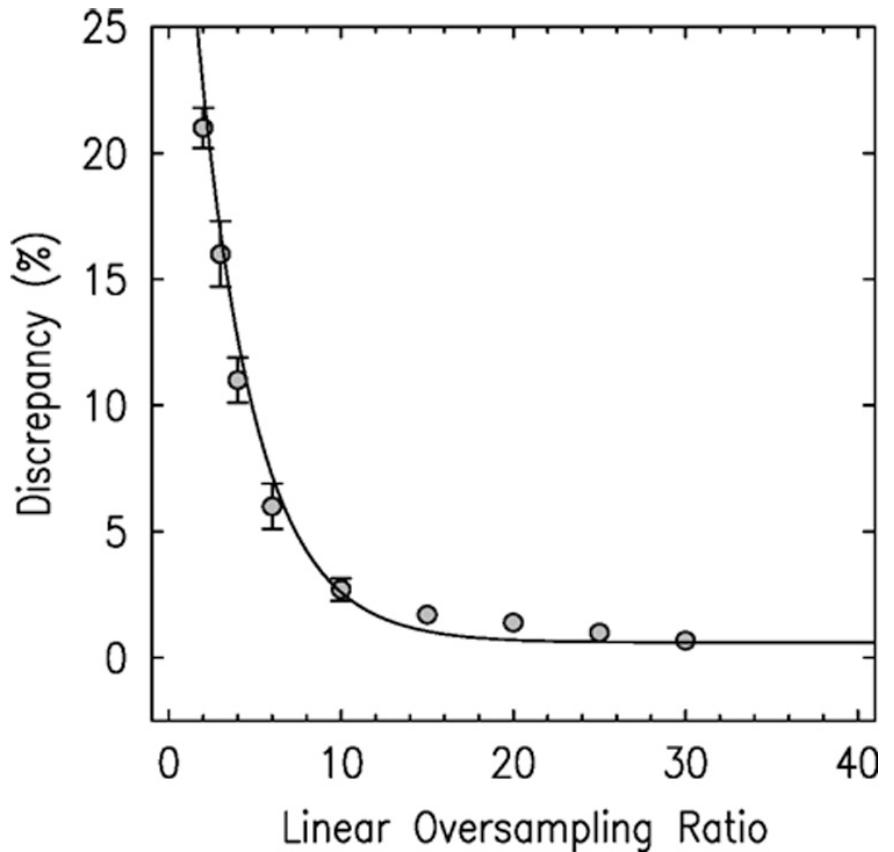


Miao, Sayre & Chapman, *J. Opt. Soc. Am. A* **15**, 1662 (1998).

## Intensity Integration vs. Exact Oversampling



Song *et al*, PRB 75, 012102 (2007).



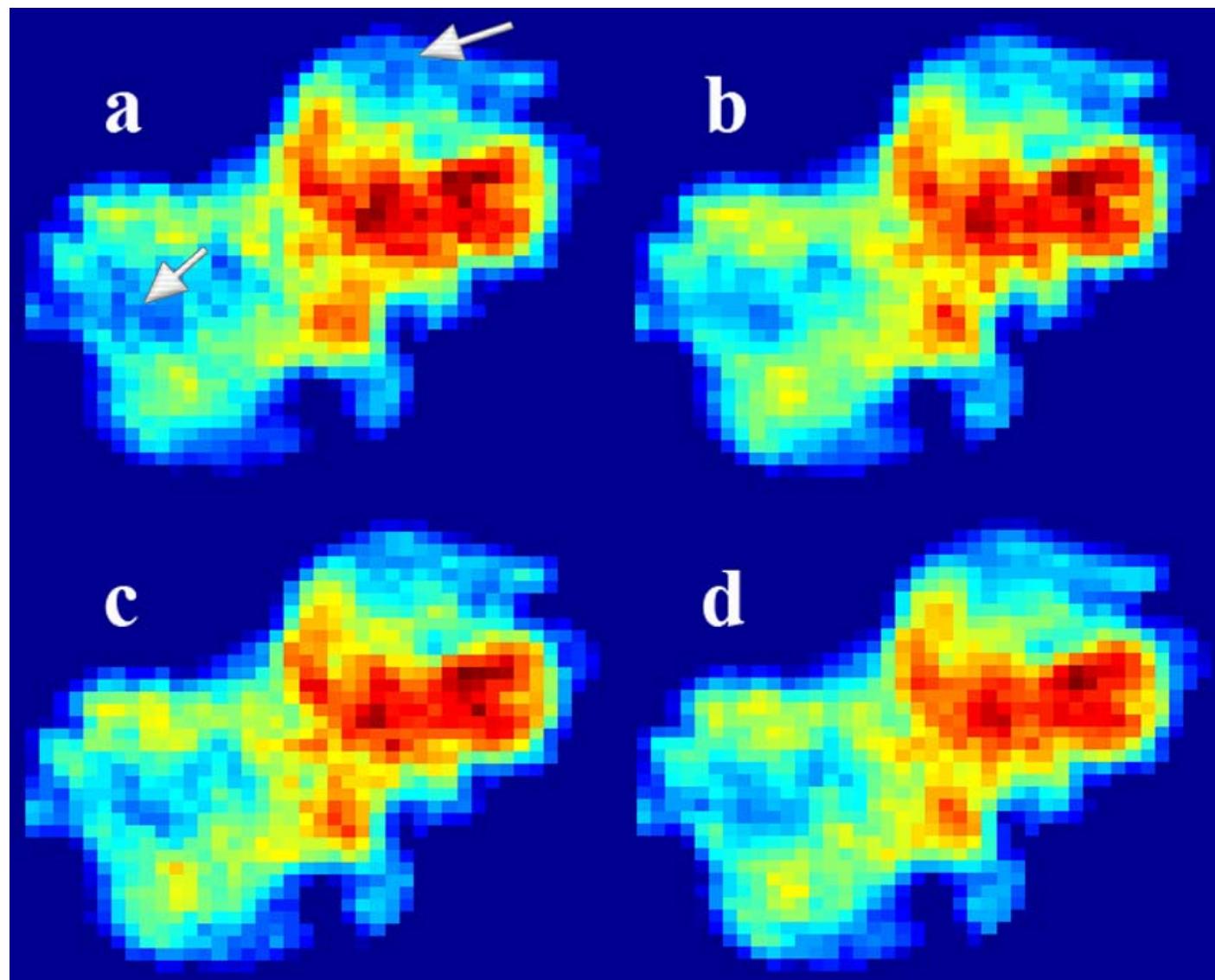
$$I_s(k) = FT \left\{ \frac{FT^{-1}[I_M(k)]}{\text{sinc}(x/M)} \right\}$$

## Experimental Verification of Exact Oversampling

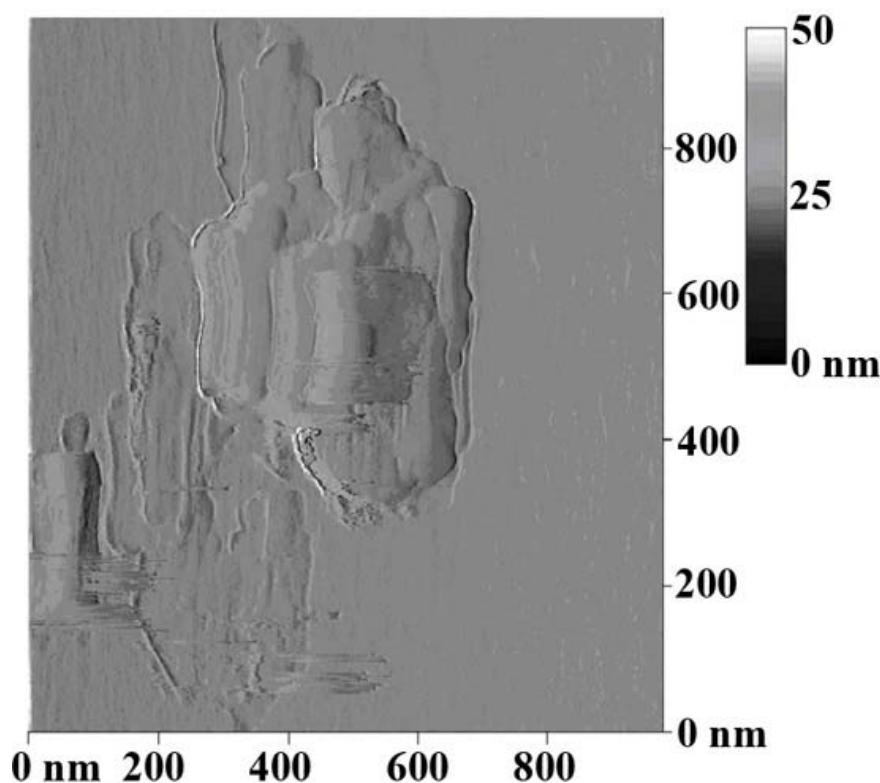
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$$\sigma_i = 2$$

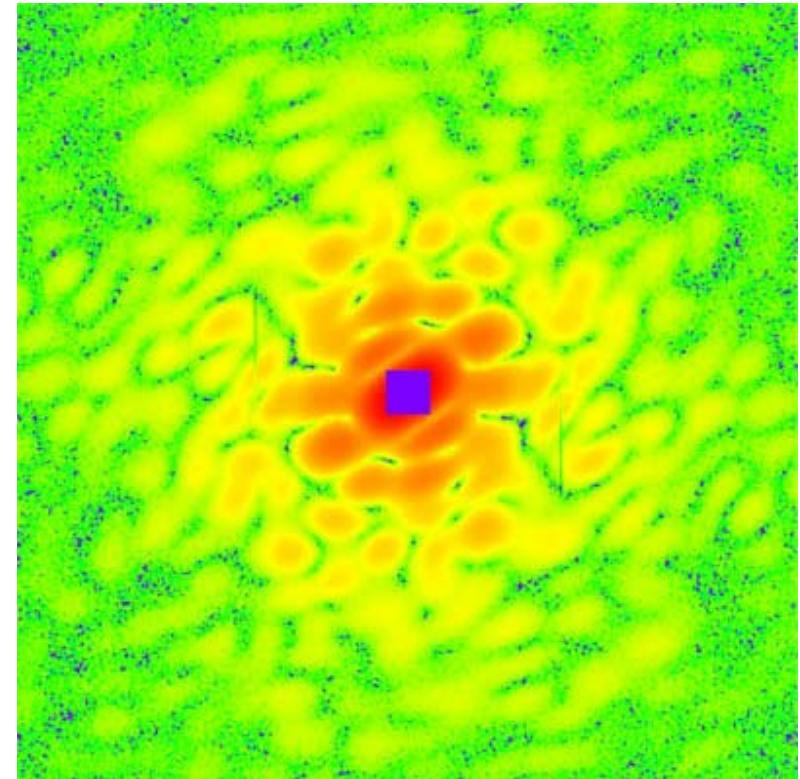
$$\sigma_i = 18$$



## The Missing Center Problem



AFM Image of GaN quantum dots,  
showing the platelet structures.



Oversampled diffraction pattern from  
a GaN quantum dot nanoparticle

$$\eta_i = \frac{D_i - 1}{2\sigma_i} \quad i = x, y, z$$

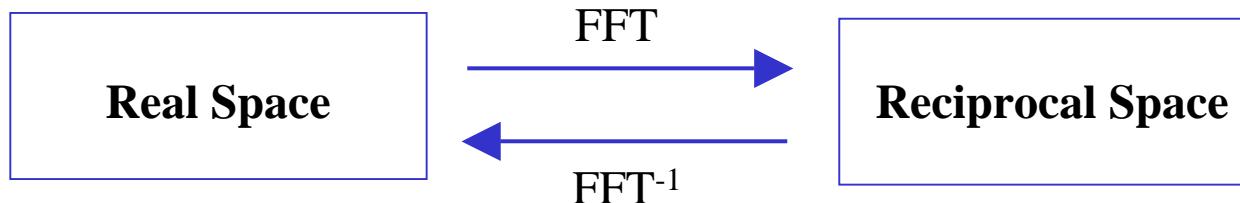
Miao *et al.*, PRL 95, 085503 (2005).

## The Guided Hybrid Input-Output (GHIO) Algorithm

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i) Start with 16 independent reconstructions.

ii) For each reconstruction:



iii) Calculate the  $R$ -value,

$$R = \sum |F_{\text{exp}}| - \alpha |F_{\text{cal}}| / \sum |F_{\text{exp}}|$$

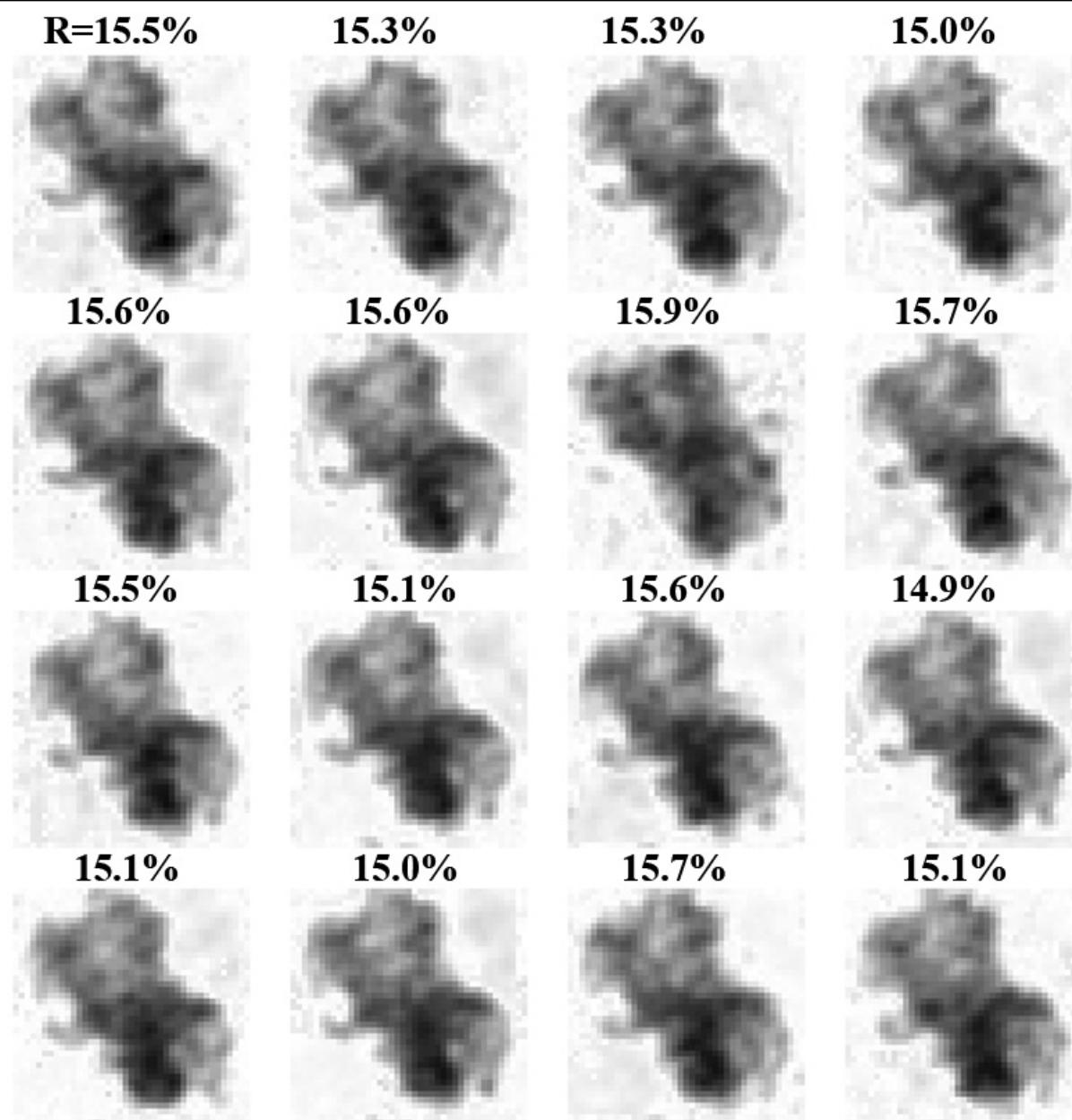
iv) Select a seed out of 16 images ( $\rho_{\text{seed}}$ ) with the smallest  $R$ -value.

v)

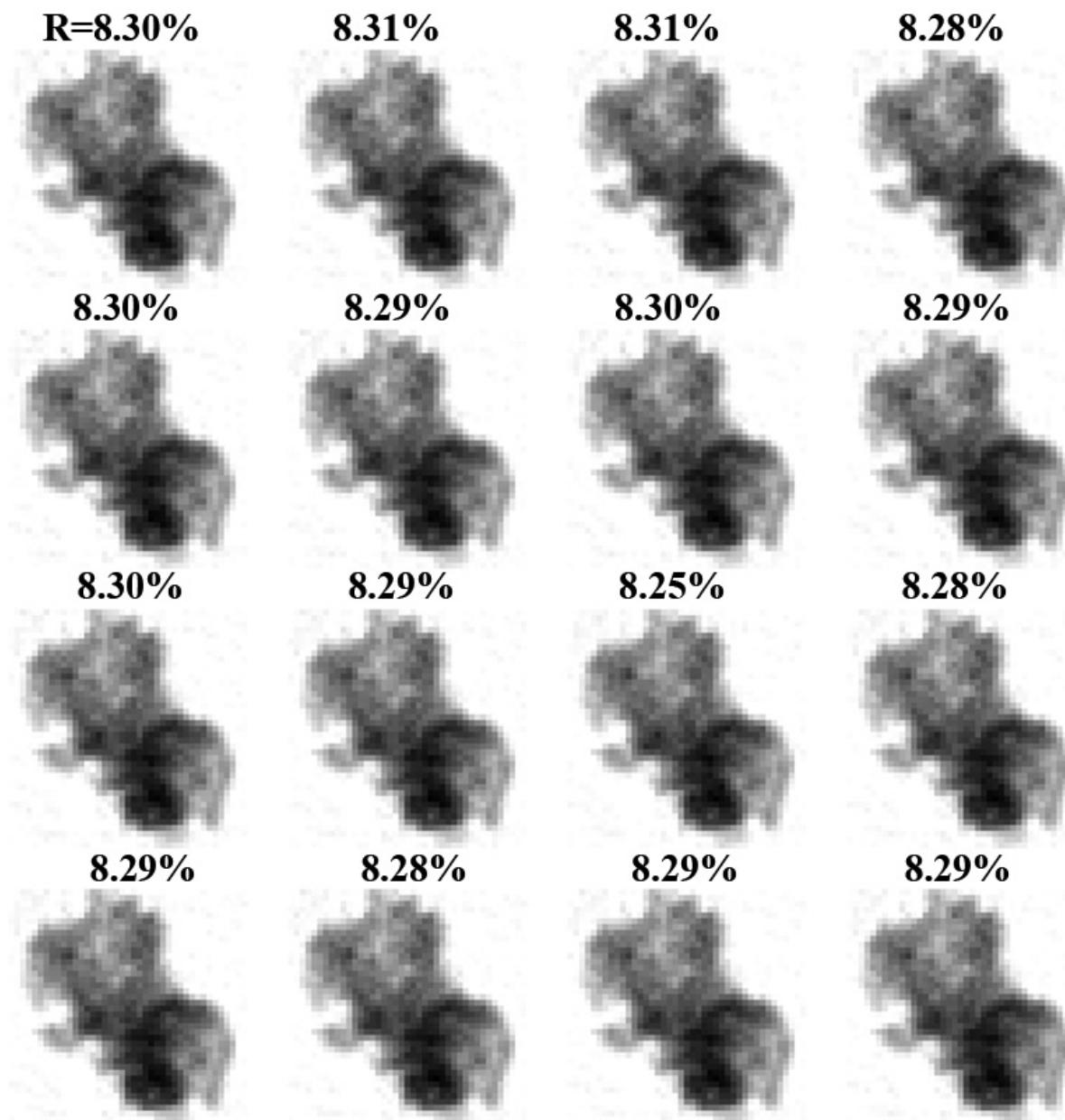
$$\rho_{\text{new}}^i = \sqrt{\rho_{\text{seed}} \times \rho_{\text{old}}^i}$$
$$i = 1, 2, \dots, 16$$

Chen *et al.*, PRB 76, 064113 (2007).

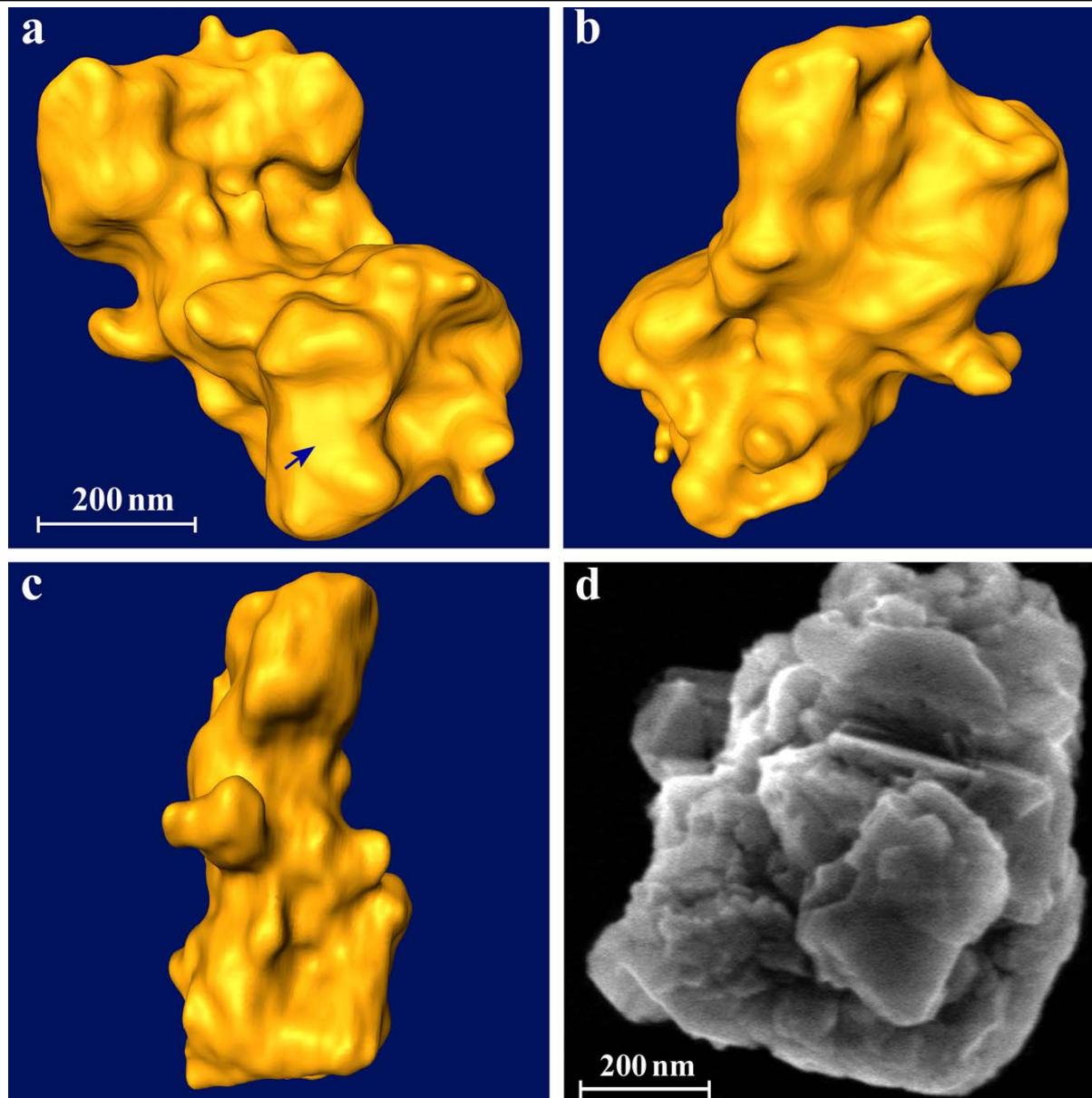
## Image Reconstruction Using the GHIO Algorithm at 0<sup>th</sup> Generation



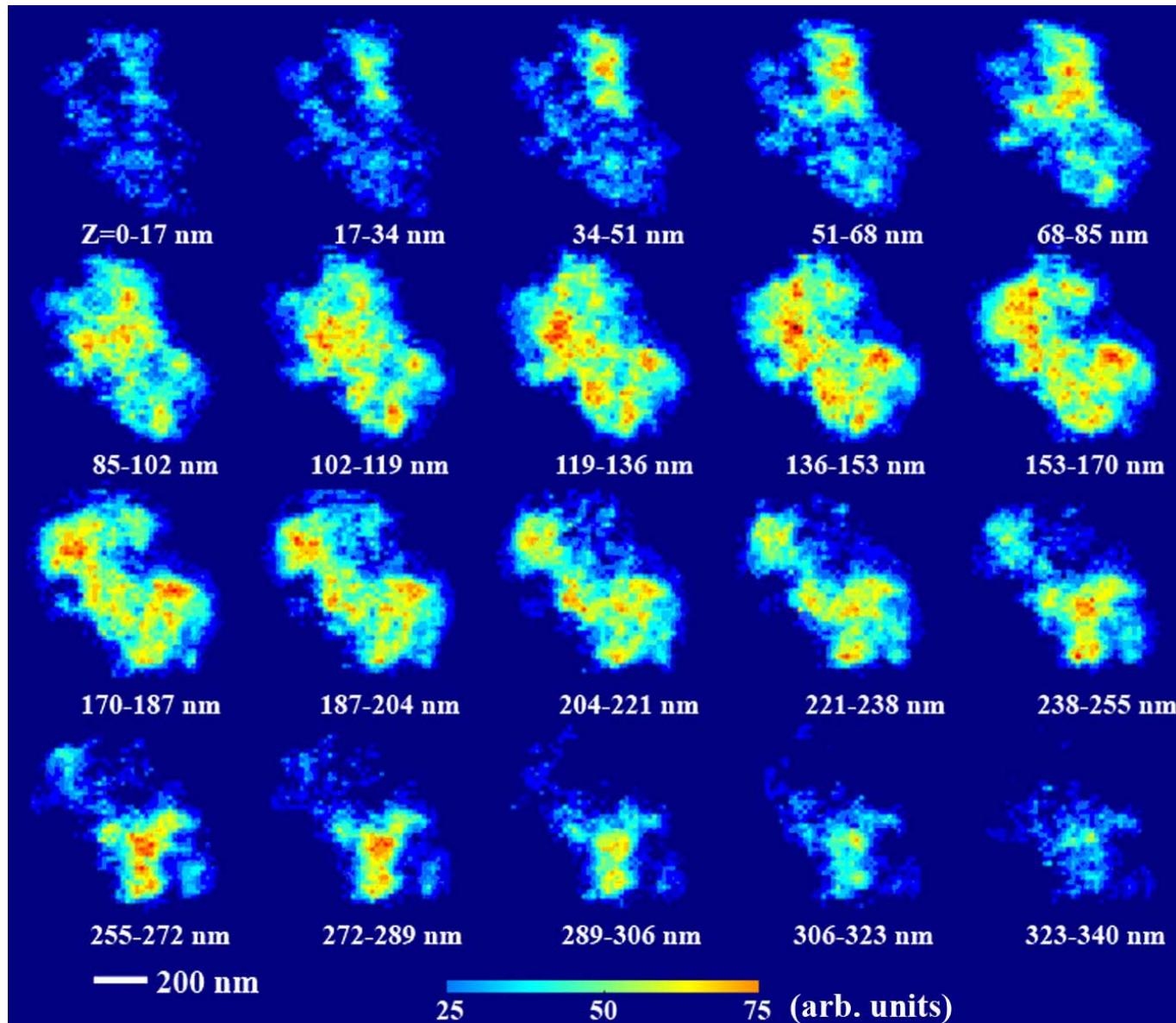
## Image Reconstruction Using the GHIO Algorithm at 8<sup>th</sup> Generation



## 3D Surface Morphology of Nanoparticles

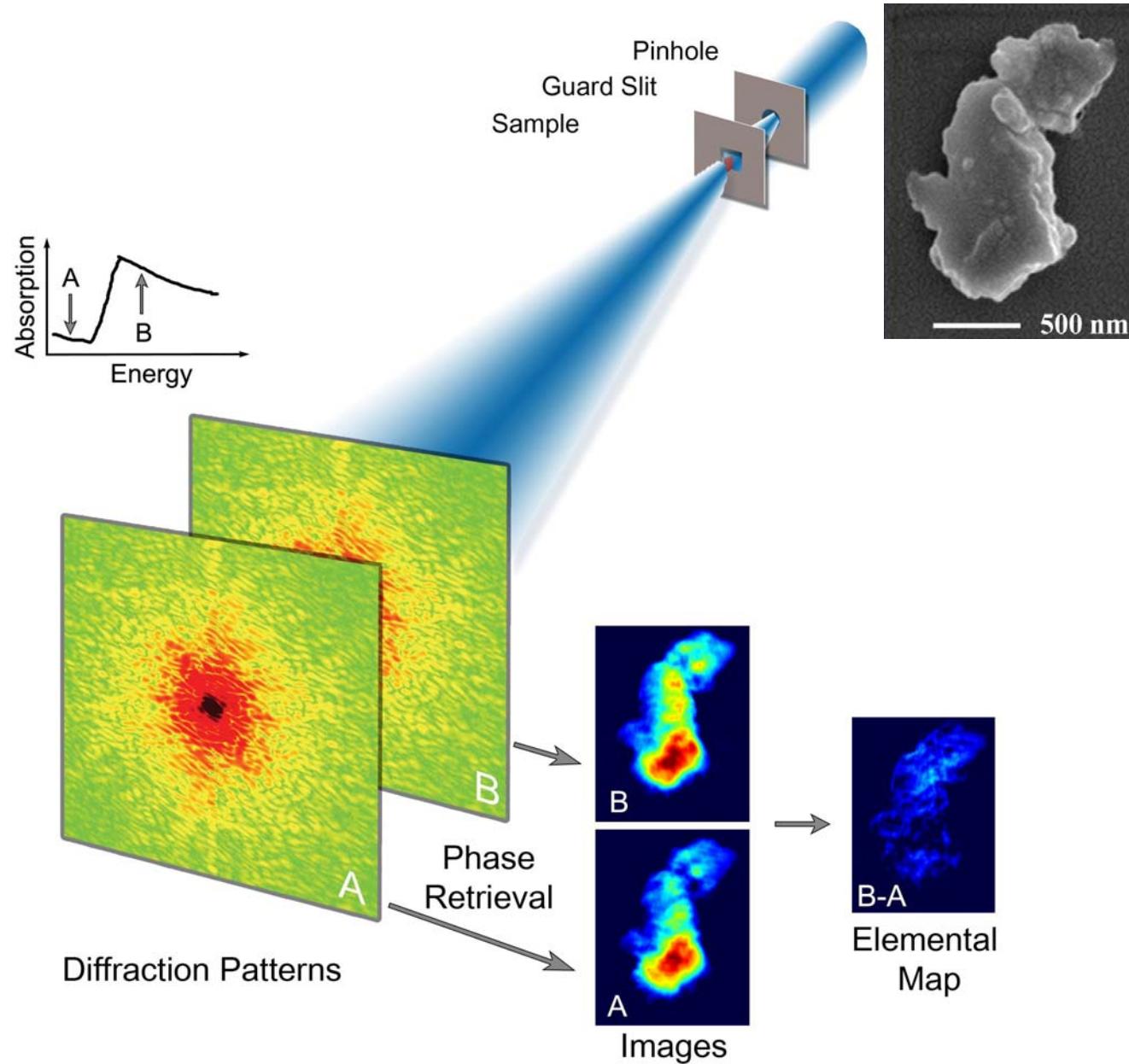


## Revealing 3D GaN-Ga<sub>2</sub>O<sub>3</sub> Core Shell Structure

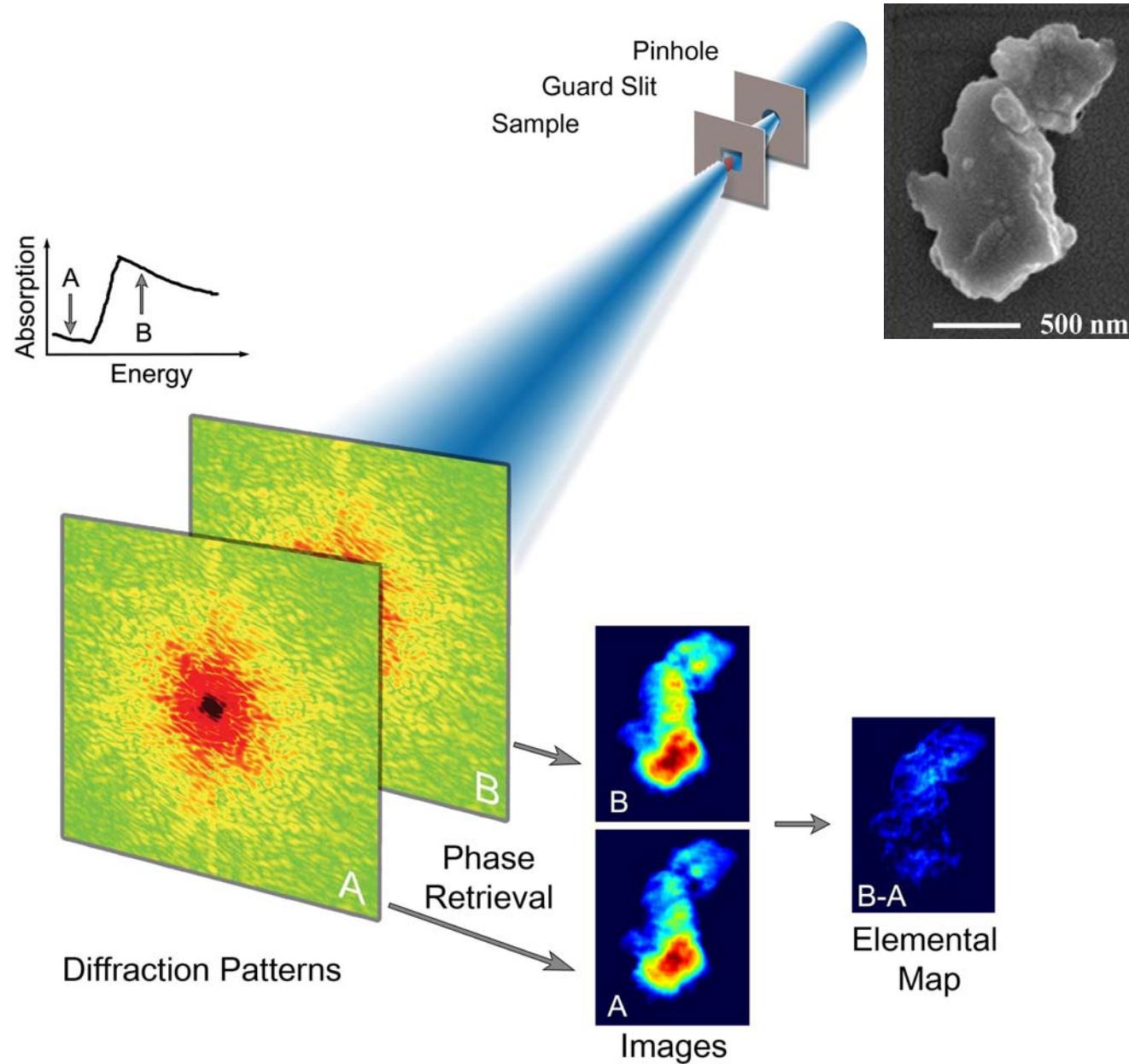


Miao *et al.*, PRL **97**, 215503 (2006).

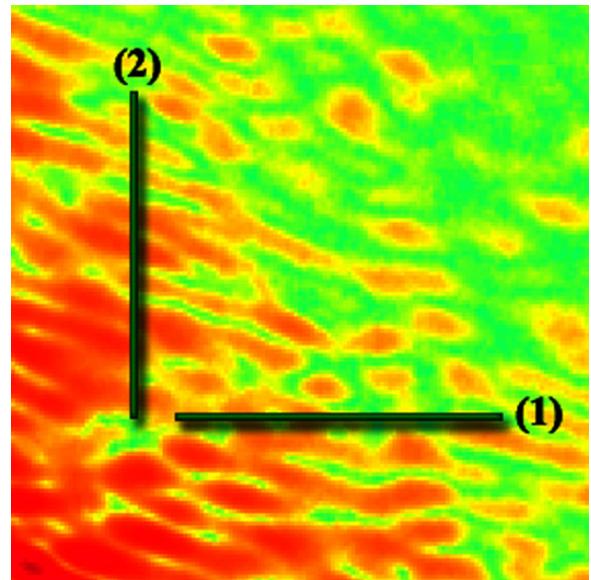
# Schematic Layout of Resonant X-ray Diffraction Microscopy



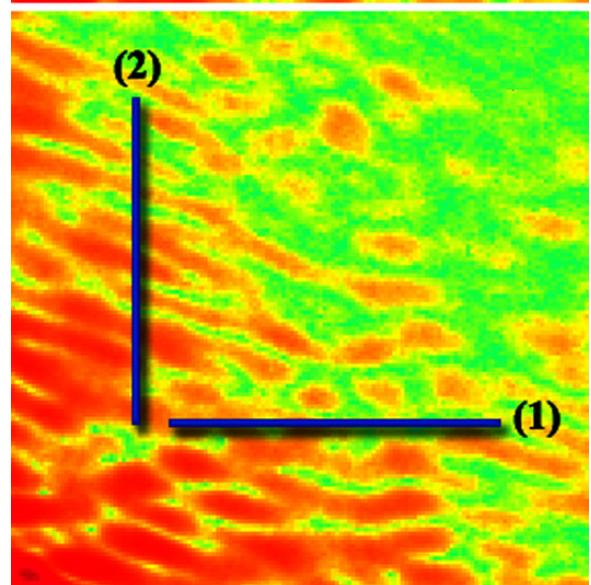
# Schematic Layout of Resonant X-ray Diffraction Microscopy



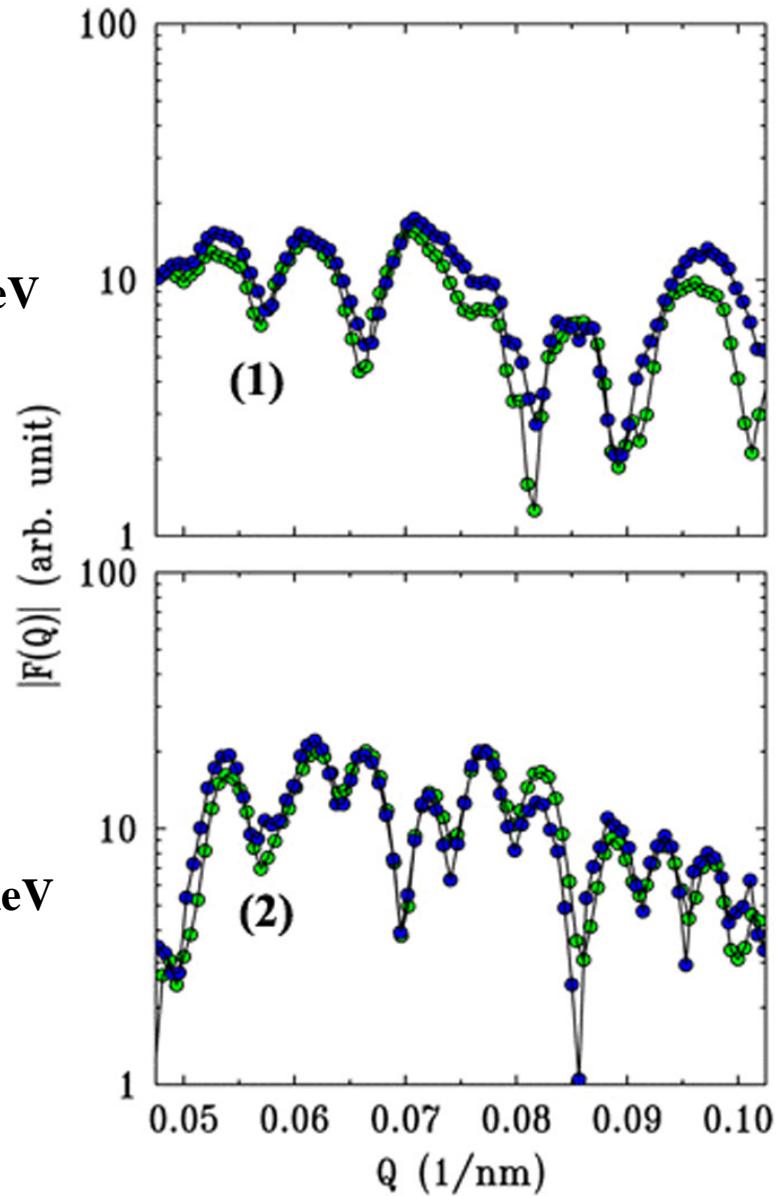
## X-ray Diffraction Patterns of a Bi Doped Si Crystal at $E=2.550$ and $2.595$ keV



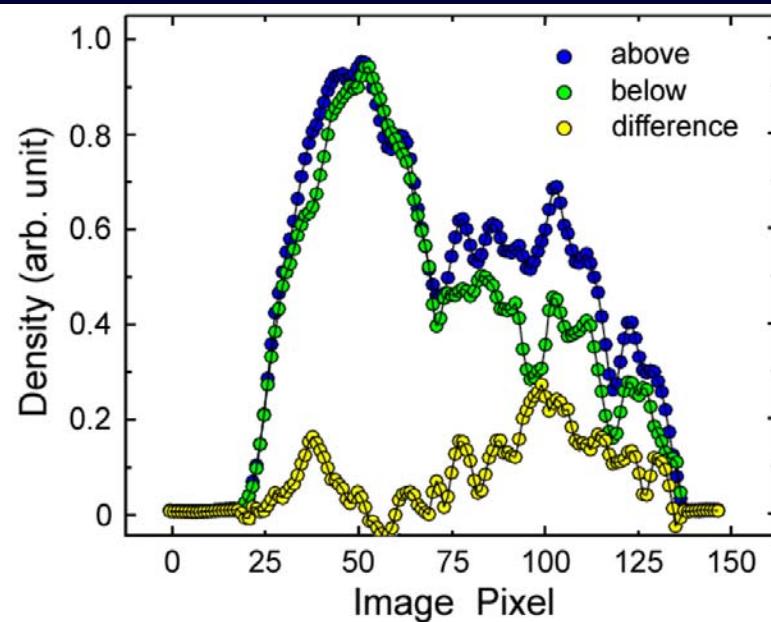
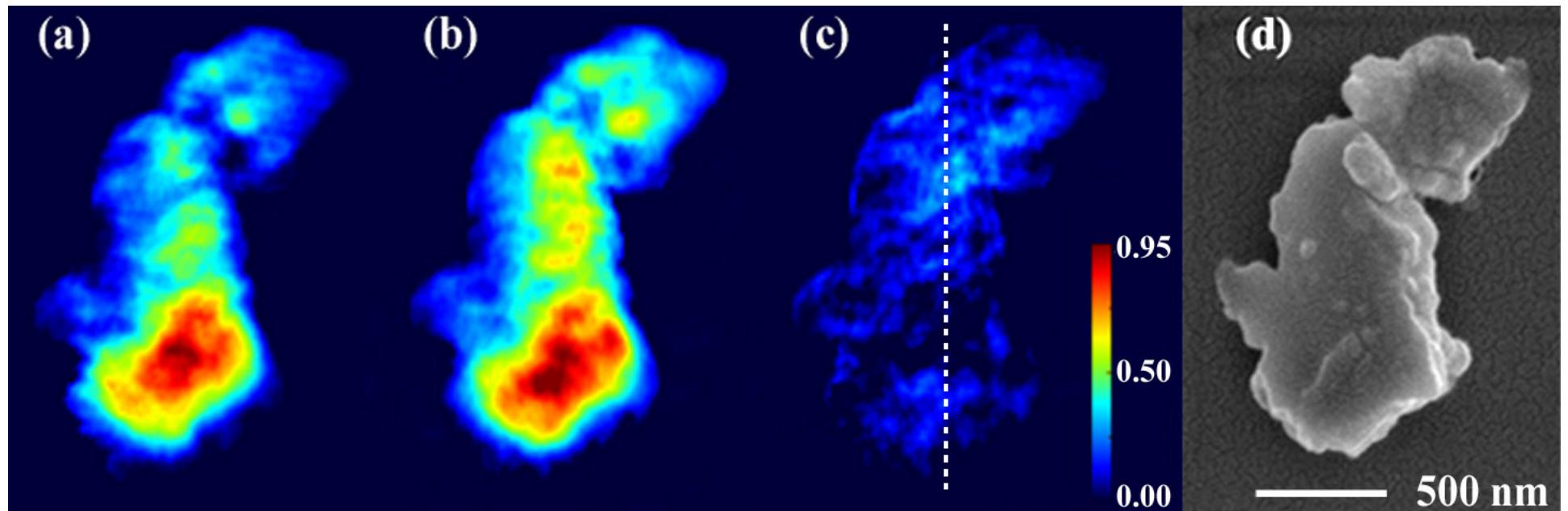
$E=2.550$  keV



$E=2.595$  keV

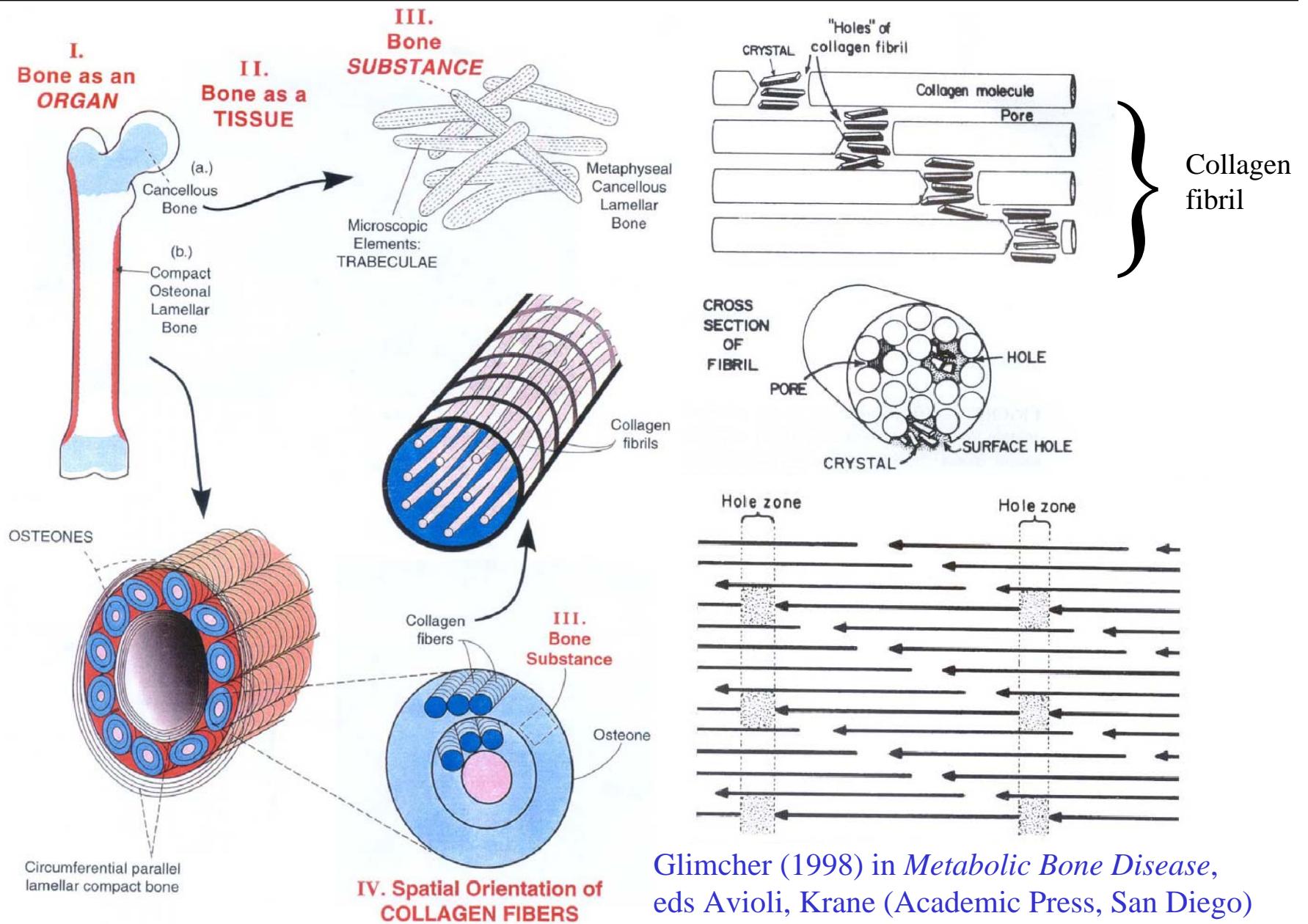


## Elemental Mapping of Buried Bi Structure



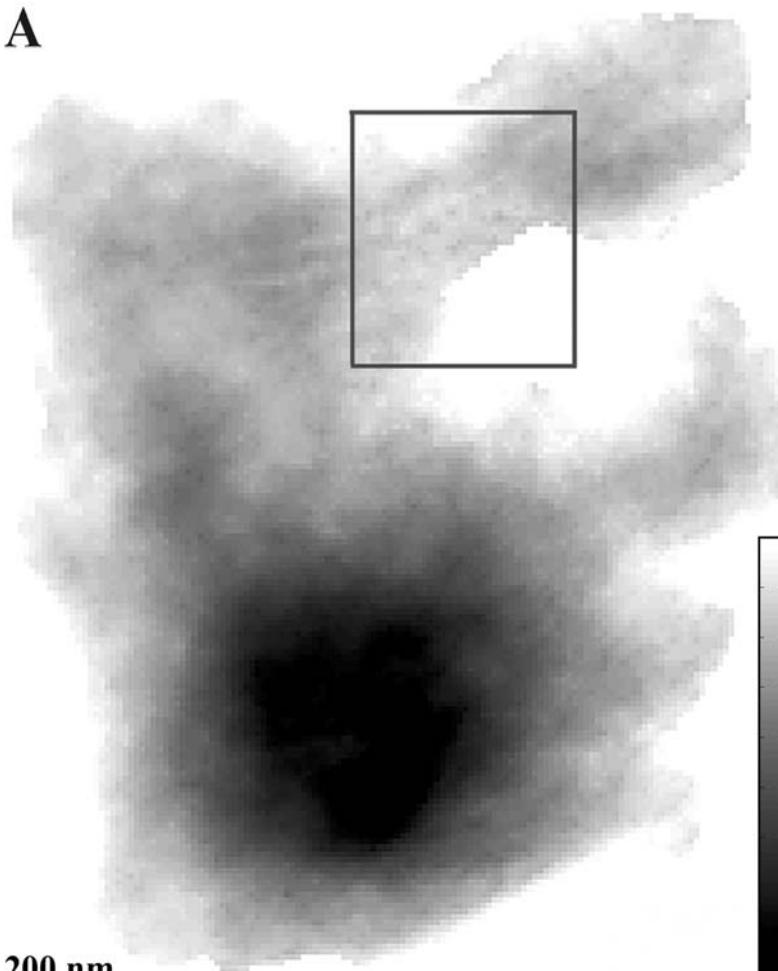
Song *et al.*, PRL 100,  
025504 (2008).

# Hierarchical Structures in Bone

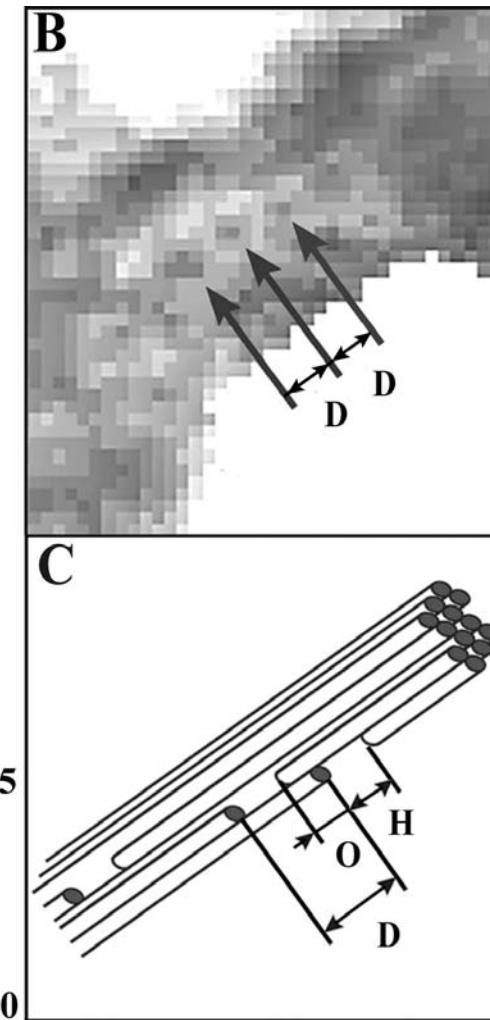


## X-ray Diffraction Imaging of Unmineralized Bone Particles

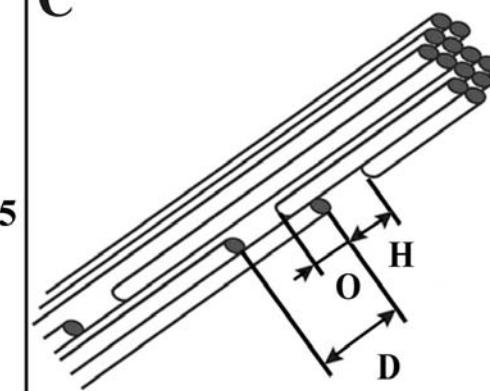
A



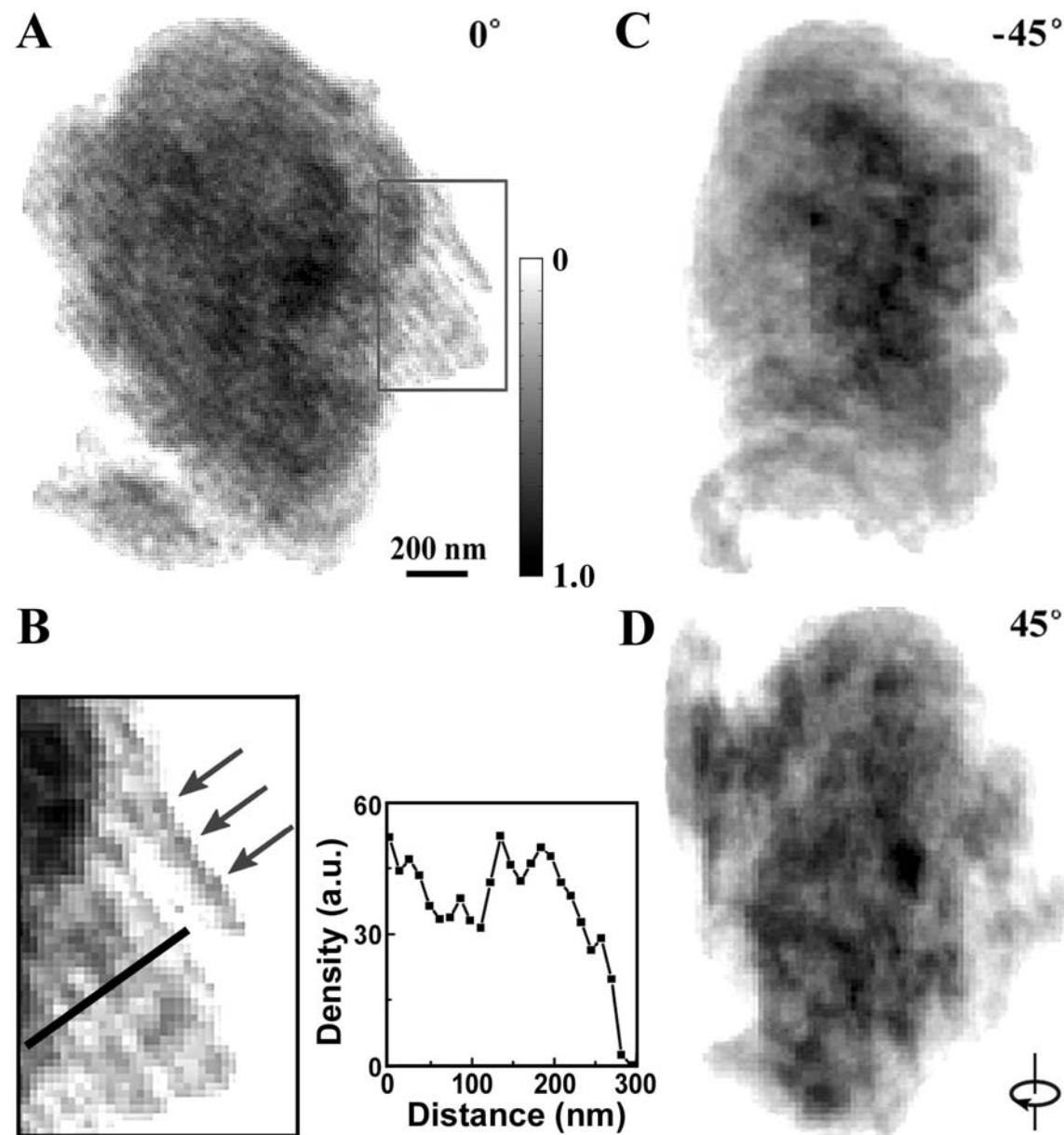
B



C

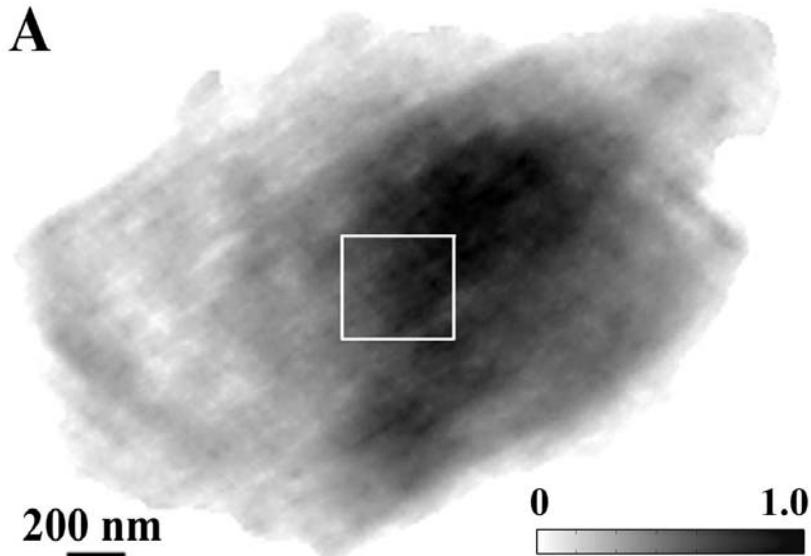


## X-ray Diffraction Imaging of Low Mineralized Bone Particles

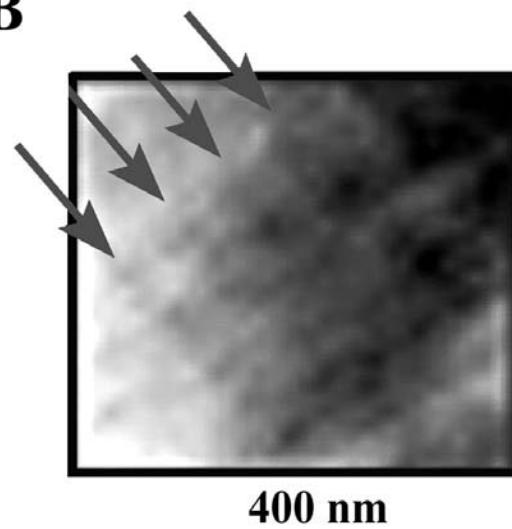


## X-ray Diffraction Imaging of Highly Mineralized Bone Particles

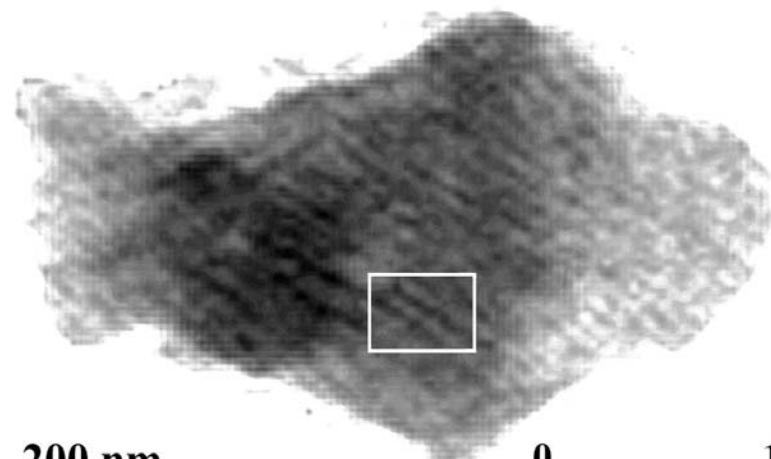
A



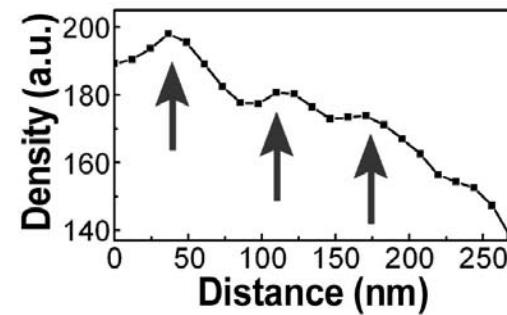
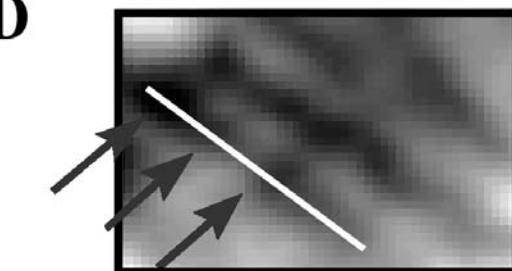
B



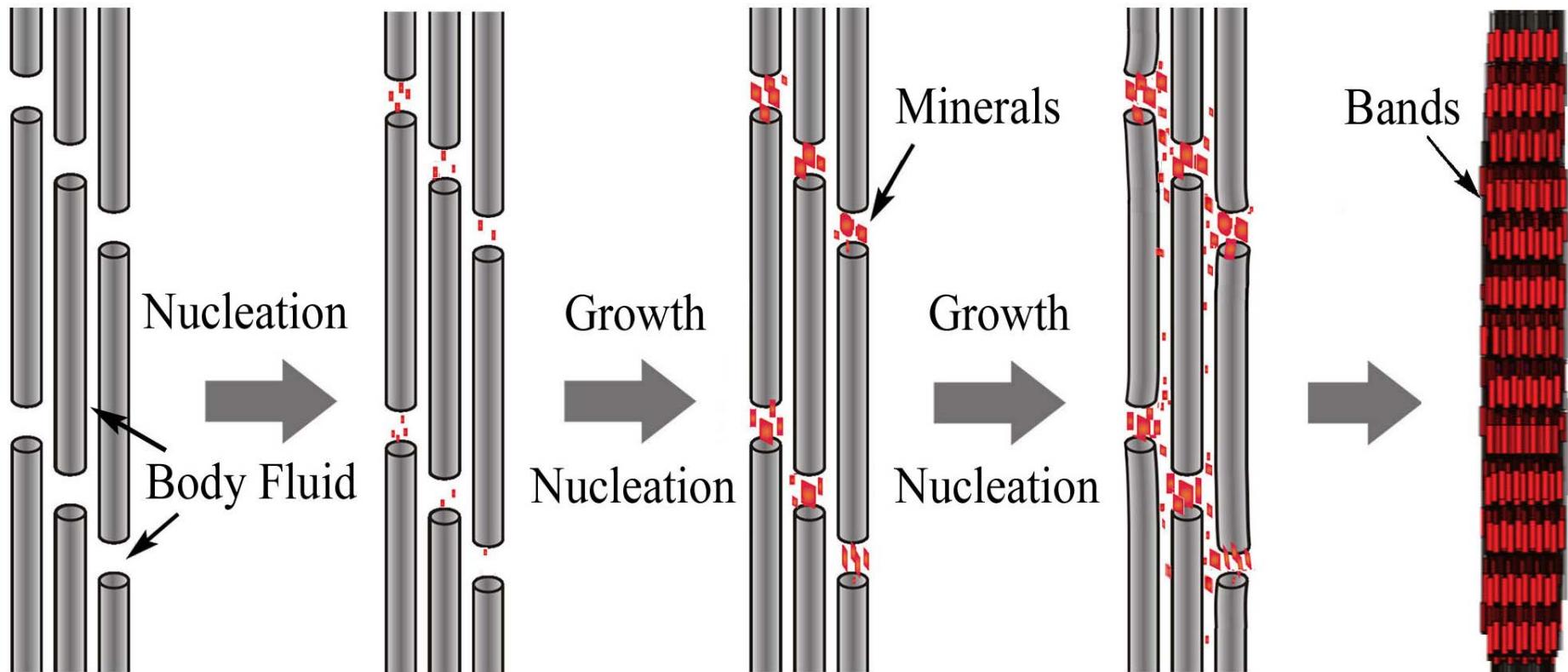
C



D



## Dynamic 3D Structure Model of the Mineral Phase in Bone



Jiang *et al.*, PRL 100, 038103 (2008).

## Summary

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- Oversampling the diffraction intensities  $\Rightarrow$  the phase information.
- Imaged nanoscale materials and biological structures in 2- and 3-dimensions.
- Resonant X-ray diffraction microscopy for element specific imaging of buried structures.
- Towards 3D structural determination of noncrystalline materials at the near atomic resolution using future brighter X-ray sources such as NSLS-II.

## Collaborators

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### UCLA, Physics & Astronomy

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### UCLA, Electric Engineering

*K. Wang*

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*S. Risbud*

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*T. Ernest*

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*M.J. Glimcher, L. Graham*